



光子晶片燒機及可靠度測試系統 Model 58604

Model 58604 Photonic IC Burn-in and Reliability Test System

產品介紹

Chroma 58604 提供各種光子晶片如雷射二極管 (LD)、光偵測器 (PD)、訊號調制器 (modulator) 等元件的老化、信賴性與壽命測試。全系統最高可支援 1,792 通道的光子晶片測試，並提供 28 個獨立溫控模組，每個模組提供高達 64 個 SMU 通道的 bi-polar 的電壓電流輸出與量測。

其產品特點在於

- 可提供各式光子晶片的老化、信賴性與壽命測試。
- 系統級別的無突波 (spike free) 電路設計。
- 高彈性的個別模組 (module) 獨立操作架構，包括獨立的通道 (SMU channel) 驅動及量測。
- 支援自動電流控制模式 (ACC) 與自動功率控制模式 (APC)。
- 精確且穩定的溫度與電路控制能力。

Chroma 58604 offers aging, reliability and lifetime testing for a wide variety of photonic chip configurations comprising laser diodes, photodiodes, modulators, etc. The system can support up to 1,792 channels of photonic chip testing and provides 28 independent temperature control modules, each capable of delivering and measuring bi-polar voltages and currents with up to 64 SMU channels.

Key product features include:

- Capability to provide aging, reliability and lifetime tests for various photonic chips.
- System-level spike-free circuit design.
- Highly flexible independent operation architecture for individual modules with independent SMU channels for sourcing and measuring.
- Support for Automatic Current Control Mode (ACC) and Automatic Power Control Mode (APC).
- Precise and stable temperature and circuit control capabilities.



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Model 58604 獨立溫控測試模組
Model 58604 Test Fixture

團隊資料



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